	ONFORMATION DISCLOSURE CITATION				Docket Number (Optional) Application Number FIS920030189US1 10/707,018						
	OHAC	RMATION DISCLOSURE	CITATION		Applicant(s) Bruce B. Doris, et al.						
88	EC 0 7	Posse several sheets if necessar 2005	**		Filing Date 11/14/03	C	Froup Art Unit	812			
•		un	U.S	. PATENT	DOCUMENTS	L		.012			
*EXAMINER INITIAL	TRADE	DOCUMENT NUMBER	DATE	·	NAME	CLASS	SUBCLASS	FILING DATE			
1 , ,	-		<u> </u>				30000033	IF APPROPRIATE			
WLL		6,281,559	8/28/01	Yu et al							
WC		6,787,827	9/7/04	Inumiya	et al.						
								1			
U.S. PATENT APPLICATION PUBLICATIONS											
*EXAMINER INITIAL	REF.	DOCUMENT NUMBER	DATE		NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE			
·											
			FORE	IGN PATE	NT DOCUMENTS						
	REF	DOCUMENT NUMBER	DATE		COUNTRY	CLASS	SUBCLASS	Translation			
		· · · · · · · · · · · · · · · · · · ·				<u></u>		YES NO			
)				
				OCUMENT							
(1		Date 09 November 2004	port and Written	Opinion,	International Application N	No. PCT/US2	vv4/v37434, In	ternational Filing			
WL											
		1			7			,			
EXAMINER MATHEMATICAL DATE CONSIDERED ///7/2006											
EXAMINE not conside	R: Initi	al if citation considered, whether clude copy of this form with next	or not citation is in	conforman	ce with MPEP Section 609; Dr	raw line throu	gh citation if not	in conformance and			
		or ima torm mitta meas		- p- p- 1- 1- 1- 1- 1- 1- 1- 1- 1- 1- 1- 1- 1-							

	H	7005	ATTY. DOCKET NO. FIS920030189US1		SERIAL NO. 10/707,018			
LIST OF PAT APPLICANT STATEMENT	ENTS AND PUBLICA'S INFORMATION DES	TIONS FOR	APPLICANT: Doris, et al.					
(Use several si	heets if necessary)		FILING DATE: 11/14/03		GROUP:			
REFERENCE I	DESIGNATION	U.S.	PATENT DOCUMENTS					
EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPRO.)		
WLL	6,228,694 B1	5/8/2001	Doyle et al.		1	Ì		
WIL	6,406,973 B1	6/18/2002	Læ					
Will	6,281,532 B1	8/28/2001	Doyle et al.	·				
WILL	5,683,934	11/4/97	Candelaria					
WILL	6,368,931 B1	4/9/2002	Kuhn, et al.					
WU	5,310,446	5/10/94	Konishi et al.					
WU	4,853,076	8/1/89	Tsaur et al.					
WU	US 2002/0090791 A1	7/11/2002	Doyle et al.					
WH	US 2002/0074598 K1	6/20/2002	Doyle et al.					
WL	6,509,618 B2	1/21/2003	Jan et al.					
W	6,476,462 B2	11/5/2002	Shimizu et al.					
W	6,362,082 B1	3/26/2002	Doyle et al.					
Wal	6,228,694 B1	5/8/2001	Doyle et al.					
LAI	5,565,697 .	10/15/96	Asakawa et al.					
Whi	US 2003/0040158 A1	2/27/2003	. Saitoh					
224	US 2002/0086472 \ 1	7/4/2002	Roberds et al.					
241	6,521,964 B1	2/18/2003	Jan et al.			7		
JUN 1	6,506,652	01/14/03	Jan, et al.	1				
		FOREIC	ON PATENT DOCUMENTS	• .				
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS 1	RANSLATION YES NO		
	OTHER	ART (Includin	g Author, Title, Date, Pertinent	Pages, etc	·.)			
	1.			·				
EXAMINER (Well T	in /	DATE CONSIDERED	1//	7/20	06		
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

班 多思测验 FORM PTO-1449 (Modified) ATTY. DOCKET NO. SERIAL NO. 10/707,018 FIS920030189US1 LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT: APPLICANT'S INFORMATION DISCLOSURE Doris, et al. STATEMENT (Use several sheets if necessary) GROUP: FILING DATE: 11/14/03 **U.S. PATENT DOCUMENTS** REFERENCE DESIGNATION **EXAMINER** DOCUMENT FILING DATE **INITIALS** NUMBER DATE NAME CLASS **SUBCLASS** (IF APPRO.) 5,081,513 1/14/1992 Jackson, et al. 3,602,841 8/31/1971 McGroddy 3/11/2003 Bosco, et al. 6,531,740 3/11/2003 Ozkan, et al. 6,531,369 6,501,121 12/31/2002 Yu, et al. 12/24/2002 Lach, et al. 6,498,358 6,493,497 12/10/2002 Ramdani, et al. 6,403,975 6/11/2002 Brunner, et al. 6,361,885 3/26/2002 Chou 6,255,169 7/3/2001 Li, et al. Brady, et al. 6,246,095 6/12/2001 Chou 6,165,383 12/26/2000 10/17/2000 6,133,071 Nagai 4/4/2000 Schetzina 6,046,464 2/15/2000 Brady, et al. 6,025,280 FOREIGN PATENT DOCUMENTS **DOCUMENT** TRANSLATION SUBCLASS NUMBER DATE COUNTRY **CLASS YES** NO OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.) DATE CONSIDERED EXAMINER

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

		- 7	2			, — — — — — — — — — — — — — — — — — — —			
FORM PTO-14	P.		HE E	ATTY. DOCKET NO FIS920030189US1		SERIAL NO 10/707,01). B		
APPLICANTS	ENTS AND PUBLICE INFORMATION DI	TIONS FOR		APPLICANT:					
STATEMENT		TE:IEM	!	oris, et al.					
(Use several sh	eets if necessary)			FILING DATE: 1/14/03		GROUP:			
REFERENCE D	ESIGNATION	U.S.	PATEN	r documents		~			
EXAMINER INITIALS	DOCUMENT NUMBER	DATE		NAME	CLASS	SUBCLA		G DATE	
WLL	5,940,736	8/17/1999	· · · · ·	Brady, et al.	CLAS	SOBCLA	35 (IF A	PPRO.)	
WU	5,880,040	3/9/1999		Sun, et al.					
WLL	5,861,651	1/19/1999		Brasen, et al.			-	-	
(NLL	5,679,965	10/21/1997		Schetzina	-				
TULL	5,670,798	9/23/1997		Schetzina				-	
WL	5,561,302	10/1/1996		Candelaria	-		_		
WLL	5,471,948	12/5/1995	В	urroughes, et al.	-	+-+			
WLL	5,459,346	10/17/1995		Asakawa, et al.		- · - -	_		
WU	5,391,510	2/21/1995		Hsu, et al.	+	-	-		
bil	5,371,399	12/6/1994	В	urroughes, et al.				+	
1,12	5,108,843	4/28/1992		Ohtaka, et al.		1	 	+	
CNU	5,060,030	10/22/1991		Hoke	-		-		
Will I	4,958,213	9/18/1990		Eklund, et al.	1	 		+	
اعالما	4,665,415	5/12/1987		Esaki, et al.	1 1			 	
1111	6,635,506	10/21/2003	•	Volant et al.	1				
		FOREIG	N PATE	NT DOCUMENTS				- †	
	DOCUMENT		*************************************				TRANSI	ATION	
	NUMBER	DATE		COUNTRY	CLASS	SUBCLASS		NO	
							<u> </u>		
	OTHER	ART (Including	Author	, Title, Date, Pertine	nt Pages, etc	-)			
	1							· ·	
EXAMINER // // DATE CONSIDERED									
AND THE REAL PROPERTY OF THE PARTY OF THE PA	Millin	Mb fr		DATE CONSIDERE		17/20	De	5	
XAMINER: Init	ial if reference consid	ered, whether or r	not citatio	on is in conformance v	with MPEP 6	09. Draw line	through c	itation if	
ot in conformance and not considered. Include copy of this form with next communication to applicant.									

		- 21									
FORM PTO-14	149 (Modified) 445 ?	S TOP B		ATTY. DOCKET NO.				IAL NO			
LIST OF PATE	ENTS AND HUBLICA	ATIONS POR		FIS920030189US1			10/	707,018	-		
APPLICANTS	INFORMATION DI	SCLOSORE		APPLICANT:							
STATEMENT	<u> </u>			Doris, et al.	·····						
(Use several sh	eets if necessary)			FILING DATE: 11/14/03			GRO	UP:			
REFERENCE D	ESIGNATION	U.S.	. PATE	NT DOCUMENTS							
EXAMINER INITIALS	DOCUMENT NUMBER	DATE		NAME	CI	ASS	SL	BCLAS		NG E	DATE RO.)
WIL	5,989,978	11/23/1999	Peidous					1		T	
WU	6,284,626	9/4/2001	Kim							7	
WLL	6,274,444	8/14/2001		Wang							
WLU	6,261,964	7/17/2001	Wu, et al.								
WU	6,221,735	4/24/2001		Manley, et al.						\top	
WLU	6,117,722	9/12/2000	Wiru, et al.							T	
wh	6,107,143	8/22/2000	Park, et al.							T	
Wi	6,090,684	7/18/2000		Ishitsuka, et al.						T	
WU	6,066,545	5/23/2000		Doshi, et al.						T	
WU	6,008,126	12/28/1999		Leedy							
M	5,946,559	8/31/1999		Leedy			·				
JAL	5,840,593	11/24/1998		Leedy							
سال	5,592,018	1/7/1997		Leedy							
UN	5,592,007	1/7/1997		Leedy					\prod		
INU	5,571,741	11/5/1996		Leedy		V					
		FOREIG	GN PAT	FENT DOCUMENTS							
	DOCUMENT NUMBER	DATE		COUNTRY	CLA	SS	SUB	CLASS	TRANS	LAT	NOI
							1300		YES	1	40
	OTHER	ART (Includin	g Auth	or, Title, Date, Pertinent	Page	s, etc	.)				
-											
EXAMINER		Ma		DATE CONSIDERED		//;	7/2	006		-27-1	_
	- Con IVV				• /			- 0			

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

	(2)			=					
449 (Modified) LH	H WAY SE								
ENTS AND PUBLICA	TIONS FOR				10/ /0/	,018			
	SCLOSURE Secretaria	Doris, et al.							
eets if necessary)		FILING DATE: 11/14/03	***************************************		GROU	P:			
ESIGNATION	U.S.	PATENT DOCUMENTS			•				
DOCUMENT NUMBER	DATE	NAME		LASS	SUB	CLASS	E .	FILING DATE (IF APPRO.)	
5,557,122	9/17/1996	Shrivastava, et al.		1			j		
5,354,695	10/11/1994	Leedy		1					
5,134,085	7/28/1992	Gilgen, et al.							
5,006,913	4/9/1991	Sugahara, et al.							
4,952,524	8/28/1990	Lee, et al.		T					
4,855,245	8/8/1989	Neppl, et al.		1				Pate 1 - 1 - 1 - 1 - 1 - 1 - 1 - 1 - 1 - 1	
2002/0086497	07-04-2002	Kwok							
5,960,297	09-28-1999	Saki	17						
6,403,486	06-11-2002	Lou							
6,284,623	09-04-2001	Zhang et al.							
2003/0032261	02-13-2003	Yeh et al.							
2003/0057184	03-27-2003	Yu et al.	\prod			7	1		
6,265,317	07-24-2001	Chiu et al.	\prod						
2003/0067035	04-10-2003	Tews et al.	П				$\neg \uparrow$		
6,461,936	10-08-2002	von Ehrenwall					$\neg \uparrow$	····	
6,319,794	11-20-2001	Akatsu et al.	П						
2001/0009784	07-26-2001	Ma et al.							
6,621,392	09-16-2003	Volant et al.						<u> </u>	
	FOREIG	N PATENT DOCUMENTS	•					-	
DOCUMENT NUMBER	DATE	COUNTRY	CL	ASS	SUBC	226			
OTHER	ART (Including	Author, Title, Date, Pertinen	<u> </u>				YES	NO	
								·····	
	7								
1//	h/h	DATE CONSIDEREI) ///	7/2	2/3/	26		<u> </u>	
ial if reference consider	red, whether or	not citation is in conformance w	ith M	1/ C PEP 60	9. Drav	w line th	rough c	itation	
	ENTS AND PUBLICAS INFORMATION DISTRICT SINFORMATION DISTRICT SINFORMATION DISTRICT SINFORMATION DISTRICT SINFORMATION DISTRICT SINFORMATION DOCUMENT NUMBER 5,557,122 5,354,695 5,134,085 5,006,913 4,952,524 4,855,245 2002/0086497 5,960,297 6,403,486 6,284,623 2003/0032261 2003/0057184 6,265,317 2003/0067035 6,461,936 6,319,794 2001/0009784 6,621,392 DOCUMENT NUMBER OTHER	## (Modified) ENTS AND PUBLICATIONS FOR SINFORMATION DISCLOSURE BESIGNATION BESIGNATION U.S. DOCUMENT NUMBER 5,557,122 9/17/1996 5,354,695 10/11/1994 5,134,085 7/28/1992 5,006,913 4/9/1991 4,952,524 8/8/1989 2002/0086497 07-04-2002 5,960,297 09-28-1999 6,403,486 06-11-2002 6,284,623 09-04-2001 2003/0032261 02-13-2003 6,265,317 07-24-2001 2003/0067035 04-10-2003 6,461,936 10-08-2002 6,319,794 11-20-2001 2001/0009784 07-26-2001 6,621,392 OTHER ART (Including DATE)	ATTY. DOCKET NO. F18920030189US1 ATTY. DOCKET NO. F18920030189US1 APPLICANT: Doris, et al. BESIGNATION U.S. PATENT DOCUMENTS DOCUMENT NUMBER DATE NAME 5,557,122 9/17/1996 Shrivastava, et al. 5,354,695 10/11/1994 Leedy 5,134,085 7/28/1992 Gilgen, et al. 5,006,913 4/9/1991 Sugahara, et al. 4,952,524 8/28/1990 Lee, et al. 4,855,245 8/8/1989 Neppl, et al. 2002/0086497 07-04-2002 Kwok 5,960,297 09-28-1999 Saki 6,403,486 06-11-2002 Lou 6,284,623 09-04-2001 Zhang et al. 2003/0032261 02-13-2003 Yeh et al. 2003/0057184 03-27-2003 Yu et al. 6,265,317 07-24-2001 Chiu et al. 2003/0067035√ 04-10-2003 Tews et al. 6,461,936 10-08-2002 von Ehrenwall 6,319,794 11-20-2001 Akatsu et al. FOREIGN PATENT DOCUMENTS DOCUMENT NUMBER DATE COUNTRY OTHER ART (Including Author, Title, Date, Pertinential if reference considered, whether or not citation is in conformance whether or not citation is in confor	### ATTY. DOCKET NO. FIS920030189US1 APPLICANT: Dor1s, et al. #### PLING DATE: 11/14/03 ###################################	### ATTY. DOCKET NO. FIS920030189US1 APPLICANT: DOCIMENT NUMBER DATE NAME CLASS 5,557,122 9/17/1996 Shrivastava, et al. 5,354,695 10/11/1994 Leedy 5,134,085 7/28/1992 Gilgen, et al. 4,952,524 8/28/1990 Lee, et al. 4,952,524 8/28/1990 Lee, et al. 4,855,245 8/8/1989 Neppl, et al. 2002/0086497 07-04-2002 Kwok 5,960,297 09-28-1999 Saki 6,403,486 06-11-2002 Lou 6,284,623 09-04-2001 Zhang et al. 2003/0037184 03-27-2003 Yeh et al. 2003/0057184 03-27-2003 Yu et al. 6,661,936 10-08-2002 von Ehrenwall 6,319,794 11-20-2001 Ma et al. FOREIGN PATENT DOCUMENTS DOCUMENT NUMBER DATE COUNTRY CLASS OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.) DATE CONSIDERED DATE CONSIDERED	### ATTY. DOCKET NO. SERIA 10/703 SINFORMATION DISCLOSURE PELICANT: Dorts, et al.	ATTY. DOCKET NO. FISSO030189US1 ATTY. DOCKET NO. FISSO030189US1 APPLICANT: Dorts, et al. FILING DATE: 11/14/03 ESIGNATION U.S. PATENT DOCUMENTS DOCUMENT NUMBER DATE NAME CLASS SUBCLASS 5,557,122 9/17/1996 Shrivastava, et al. 5,354,695 10/11/1994 Leedy 5,134,085 7/28/1992 Gilgen, et al. 4,952,524 8/28/1990 Lee, et al. 4,855,245 8/8/1989 Neppl, et al. 2002/0086497 07-04-2002 Kwok 5,960,297 99-28-1999 Saki 6,403,486 06-11-2002 Lou 6,284,623 09-04-2001 Zhang et al. 2003/0057184 03-27-2003 Yeb et al. 2003/0057184 03-27-2003 Yeb et al. 2003/0057035 Tews et al. 6,461,936 10-08-2002 Von Ehrenwall 6,61,936 10-08-2002 Von Ehrenwall 6,621,392 09-16-2003 Volant et al. 2001/0009784 OT-26-2001 Ma et al. 6,621,392 O9-16-2003 Volant et al. DOCUMENT NUMBER DATE COUNTRY CLASS SUBCLASS DATE COUNTRY CLASS DATE COUNTRY CLASS SUBCLASS DATE COUNTRY CLASS SUBCLASS DATE COUNTRY CLASS DATE COUNTRY CLASS SUBCLASS DATE COUNTRY CLASS DATE COUNTRY CLASS SUBCLASS DATE COUNTRY CLASS COUNTRY CLASS DATE COUNTRY CLASS DATE COUNTRY CLASS DATE COUNTRY CLASS CANDRADE COUNTRY CLASS COUNTRY	### ATTY. DOCKET NO. SERIAL NO. 10/707,018 ### ATTY. DOCKET NO. FISSO0301889US1 10/707,018 ### APPLICANT: DOCUMENT DOCUMENT NUMBER DATE NAME CLASS SUBCLASS FILIN NAME NA	

	INFO	rmation disclosuré	CITATION	FIS920030189US1		10/707,018				
		(Use several sheets if necessa	LEB ANDER	Doris, et al. mag Date 11/14/03		Greep Art Unit				
		\a	EEB	Ö 11/14/03						
		V	EN	U.S. PATENT DOCUMENTS		····				
*Examiner Pottal	REF	DOCUMENT NUMBER	DATE	IWE	CLASS	22ADGUA	FILING DATE FAPPROPRIATE			
		5,940,716	8/17/1999	Jin, et al.						
UCY		6,483,171 B1	11/19/02	Forbes, et al.						
MCL	/	2002/0063292 A1	5/30/02	Armstrong, et al.	·	·				
,	. //	. 25	. 4							
					•					
		·								
							1			
						<u> </u>				
·		·								
						·				
				FOREIGN PATENT DOCUMENTS	·					
	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	\$UBCLASS	YES NO			
		JP64-76755	03-1989	Japan						
					··					
							•			
				OTHER DOCUMENTS (Including A)	nthor, Title, D	ate, Pertinent Pag	ca, Esc.)			
~	1			·		_				
				Α.						
·										
EXAMINER	Th)			DATE CONSIDERED	1171	2000	6			
EXAMINER not consider	EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.									
										

••	FORM PTO-1449 (Mo		ATTY. DOCKET NO. FIS920030189US1		SERIAL NO. 10/707,018	
LIST OF PATT APPLICANTS STATEMENT	ENTS AND PUBLICA SINFORMATION PIE	Tri Ochre (%)	APPLICANT: Doris, et al.			
(Use several sh	eets if necessary)	FEB 3. 5 JULY 3.	FILING DATE: 11/14/03		GROUP:	
REFERENCE D	ESIGNATION	de zastus	PATENT DOCUMENTS		· .	
EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPRO.)
					}	
	·					
	<u> </u>	FOREI	GN PATENT DOCUMENTS			
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
	OTHER	ART (Includi	ng Author, Title, Date, Pertine	nt Pages, etc	2.)	
WU	Kem Rim, et al., International Elec	Transconductation Devices M	ance Enhancement in Deep S leeting, 26, 8, 1, IEEE, Septe	Submicron S mber 1998.	Strained-Si n-M	OSFETs",
WL	2002 Symposium	On VLSI Tech	s and Device Design of Sub-1 nology Digest of Technical Pa	apers, IEEE	, pp 98-99.	
NU	Isolation Induced	Stress*, Intern	ive Current Reduction Cause ational Electron Devices Mee	ting, 34.4.1	, IEEE, Septen	nber 1999.
214	F. Ootsuka, et al., Scale System-on- 2000.	, "A Highly Den a-Chip Applica	se, High-Performance 130nm tion", International Electron C	n node CM(Devices Med	OS Technology eting, 23.5.1, it	for Large EEE, April
AU	Shinya Ito, et al., Transistor Design	'Mechanical St ', International	ress Effect of Etch-Stop Nitric Electron Devices Meeting, 10	de and its Ir 0.7.1, IEEE	npact on Deep , April 2000.	Submicron
Jue	Enhancement, In	temational Ele	nical-Stress Control (LMC): A ctron Devices Meeting, IEEE,	March 200	1.	
MU	K. Ota, et al., "No International Elec	vel Locally Stra tron Devices M	ined Channel Technique for I eeting, 2.2.1, IEEE, February	high Perform 2002.	mance 55nm C	MOS",
EXAMINER	Ma Tun	Sh.	DATE CONSIDERE	1//	1/2006	
XAMINER: Inition of in conformance	tial if reference considered.	ared, whether or Include copy of	not citation is in conformance w	ith MPEP 6	09. Draw line ti ant.	rough citation if

	INFO	DMATION DISCI OSIDE	CONTION	Sign Control	Docket Number (Optional) FIS920030189US1 Applicant(s)	·	Application Number 10/707,018	er.
	HALO	RMATION DISCLOSURE (Use several sheets if necessa	e Creation	NE 124				
		tore several anerra à incress	7 7 5 3		Doris, et al. Filing Date		Group Art Unit	
			FER 7.55 T	KOELCE,	11/14/03			
			U.S.	PATENT	DOCUMENTS			
•EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE		NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
			U.S. PATENT	APPLICA	TION PUBLICATIONS			/
*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE		NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	1 (1)							
								\rightarrow
			FOREI	GN PATEN	IT DOCUMENTS			
	PARTY	DOCUMENT NUMBER	DATE		COUNTRY	CLASS	SUBCLASS	Trusslation YES NO
							<u>.</u>	
								1
			OTHER D		•		ertinent Pages, E	
Wil		G. Zhang, J. Cressler, G SiGe Bipolar Transistor	·					
WU		H.S. Momose, Y. Niitsu, its Mechanism Analyzed	H. Iwai, K. Maeg by MOS Structu	uchi, "Te res". Pap	mperature Dependence er 6.2, pp. 140-143.	of Emitter-Bas	e Reverse Stres	s Degradation and
EXAMINE	R ///	Jh 1/2 /h //			DATE CONSIDERED	1/1717	2006	
EXAMINE not conside	R: Initi	al if citation considered, whether clude copy of this form with next	or not citation is in c communication to a	conformant pplicant.	re with MPEP Section 609;			in conformance and

,					Docket Number (Ontional)		Application Numbe	7	
	DIEC	NO SE A TOTAL DICOL ACTION	Carried Street		FIS920030189US1 Applicant(s)		10/707,018		
	TALC	DRMATION DISCLOSURA (Use several sheets if necessi	CHAILON	.)	**		•		
l			Alle is a	301	Doris, et al		Group Art Unit		
		; 	सम्	H	11/14/03				
		(5)	, W	PATENT	DOCUMENTS				
*EXAMINER	REF	DOCUMENT NUMBER	DATE		RAME	CIVE	SUBCLASS	FILE	ig date
INITIAL	-		 	 		 		IF APP	ROPRIATE
-		1	 				1		
			 						\
	<u> </u>	·	II C DATEN	F A P.D.L. I.C.A.	TION PUBLICATIONS	<u> </u>			
*EXAMINER	1		T .	AFFLICA		l .	7	571.00	G DATE
DITTAL	REF	DOCUMENT NUMBER	DATE		NAME	CIASS	SUBCLASS		OPRIATE
									* ****
					······································			-	
								\gg	ノ
			FORE	ign paten	T DOCUMENTS				
	REF	DOCUMENT NUMBER	DATE		COUNTRY	CLASS	SUBCLASS	Yes	station NO
/									
								1	
									3
					······································				
			OTHER D	OCUMENT	S • Ancluding Author,	Title, Date, Pe	rtinent Pages, Etc	 (<u>:</u>	L
	T	C.J. Huang, C.J. Sun, T.	A. Grotjohn, D.K	C Reinhard	"Temperature Depender 1991 Bipolar Circuits and	-	-	-	lectron
MU									
WL	1	S.R. Sheng, S.P. McAllist Hot-Carrier Stressing [®] .	er, J.P. McCaffr Pp. 14-15.	ey, S. Kov	cic, "Degradation and Re	covery of Sid	Ge HBTs Foliow	ving Radis	bas noits
EXAMINE	M	alde I. Ludali-		1	DATE CONSIDERED	17/20	000		
EXAMINES not consider	R: Initia red. Inc	l if citation considered, whether or dade copy of this form with next co	r not citation is in communication to a	conformance pplicant.	with MPEP Section 609; Dr	aw line throug	ch citation if not i	n conform	ance and

•	•				Docket Number (Optional)		Application Numb	
		•	KIPE		FIS920030189US1		10/707,018	
	INFO	RMATION DISCLOSUI	RECEPATION 4	<u>(3)</u>	Applicant(s)			
		(Use several sheets if nece	1	18	Doris, et al.			
			FEB 2.5 7008	1 19	Filing Date	*	Group Art Unit	
			EA	¥.	11/14/03	······································		
			Y . T.	.~	DOCUMENTS			
'EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE		NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
								PATROPRIATE
					 			
٠.		-						
							-	
							+	
			U.S. PATENT	APPLICA	TION PUBLICATIONS			
*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	····	NAME	CLASS	SUBCLASS	FILING DATE
/						1		IF APPROPRIATE
				····				
						4		1
						+		
								7
			FOREIC	GN PATEN	T DOCUMENTS			
	REF	DOCUMENT NUMBER	DATE		COUNTRY	CLASS	SUBCLASS	Translation YES NO
					·			
74	\forall		1					
			 	<u></u>	 			
ĺ			1				j	İ
								>
						-		
		***	A	A. A			<u> </u>	
		17 Vers B Courte E	OTBER DO		•		-	
1.41		Z. Yang, P. Gaurin, E. Heterojunction Bipolar	Transistors". Pp.	ian, "Avai 1-5.	lanche Current Induced	Hot Carrier D	egradation in 2	00GHz SiGe
WIL							,	
		H. Li, H.M. Rein, T. Su Automotive Radar Syst	ttorp, "Design of W	-Band V	Os with High Output P	ower for Poten	tial Application	a la 77 GHz
1111		Automotive Radar Syst	ems". 2003 IEEE (CaAs Dige	st, pp. 263-766.			
0000						- v · V -		
-	Щ,							
EXAMINER	hla	What had	1.	ľ	DATE CONSIDERED	1/17/2	2006	,
EXAMINER of consider	t initial	if citation considered, whether	or not citation is in co	aformance				
		bl as me tales with mem						

	•				Docket Number (Ontional)		Application Numb	tr
l	D.MO.		IFE.		FIS920030189US1		10/707,018	
	INFO	MATION DISCLOSÚRE (Use several sheets ty/necesse			Apolicant(s)			
l					Doris, et al.		Group Art Unit	
		12	ω		11/14/03			
		E.	دىلاد	PATENT	DOCUMENTS			
	1 1	***	THE COURT OF THE PARTY OF THE P					
*EXAMINER DITTAL	REF	DOCUMENT NUMBER	DATE		NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
7								- ATTROPRIATE
	\vdash				<u> </u>			
							_	
••	''	.				1	1	
	<u></u>		U.S. PATENT	APPLICA'	TION PUBLICATIONS			
*EXAMINER	Т	· · · · · · · · · · · · · · · · · · ·						
DITTAL	REF	DOCUMENT NUMBER	DATE		NAME	CLASS	SUBCLASS	Filing date If appropriate
)								
ψ			FOREI	GN PATEN	T DOCUMENTS			
	REF	DOCUMENT NUMBER	DATE		COUNTRY	CLASS	SUBCLASS	Translation YES NO
					,			
	LI.,	and the second s	ANGTON N	WALE TANKS	Ø # # 4 -	han 774- 5 "		
		III Warren D Makedon		OCUMENT	,	hor, Title, Date, P	- -	
	i	H. Wurzer, R. Mahnkop Transactions on Electron	Devices, vol. 41,	no. 4, Apr	ii 1994, pp. 533-538.	1012- Wicchminzin	z ano zrodenik	o effect;
WLL	-							
	_	B. Doyle G.J. Dunn. hR.	ecovery of Hot-C	arrier Dam	age in Reoxidized Nit	rided Oxide MO	SFET IEE	E Electron Device
WU		B. Doyle, G.J. Dunn, "R Letters, vol. 13, no. 1, Ja	nuary 1992, pp. 3	8-40.	0			
WU			- 1					
		11	1.//			17	1/22 =	
EXAMINE	R///	BI Time	16 h.		DATE CONSIDERED	1/17/	1200	6
		if citation considered, whether o			e with MPEP Section 609	; Draw line thro	gh citation if not	in conformance and
not consider	red. lad	ide copy of this form with next c	ommunication to a	pplicant.				

	•				Docket Number (Optional)		Application Numb	tr
j	INFO	RMATION DISCLOSUE	POTATION		FIS920030189US1 Applicant(s)		10/707,018	
1	Life	(Use several sheets if neod	sary)		Doris, et al.			
			is anne	1.	FWing Date		Group Art Unit	
		·	EB 15 MG		11/14/03			
		¥	7.9	PATENT I	DOCUMENTS			
*EXAMINER INITIAL	REF	DOCUMENT NUMBER	E MAREN		NAME	CIASS	SUBCIASS	FILING DATE
/								IF APPROPRIATE

					_			
			U.S. PATENT A	APPLICAT	TON PUBLICATIONS			
•EXAMINER INITIAL	227	DOCUMENT NUMBER	DATE		NAME	CLASS	SUBCLASS	FILING DATE
								IF APTROPRIATE
								\

1			FOREIG	N PATENT	DOCUMENTS		1	
	277		T			/**-**********************************	T	Translation
	<u></u> -	DOCUMENT NUMBER	DATE		COUNTRY	CLASS	SUBCLASS	YES NO
						A.		
						_		
,								
						-		
			OTHER DOC	UMFNTS	(Including Author,	Title Date De	risent Duncer Etc.	
	Ţ	H.S. Momose, H. Iwal, Transistors for Bi-CMC			•			
1117	i	Transistors for Bi-CMC	S". IEEE Transact	ions on El	ectron Devices, vol. 41, n	o. 6, June 19	94, pp. 978-987.	
MM		ĺ						
					1			
	+	+,						
	برا					· · · · · · · · · · · · · · · · · · ·		
EXAMINER	Will	# 1 Frankle M		D.	ATE CONSIDERED	117/2	2006	
XAMINER	: initial i	if citation considered, whether of de copy of this form with next of	or not citation is in con	formance v	rith MPEP Section 609; Dri	w lize throug	b citation if not in	conformance and
	- 1144	or cohl or mis inten mirri seri (·····			